SHEET OF 2 ATTY DOCKET NO. SERIAL NO. U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE Form PTO 1449 (Modified) 237565US0 10/812.956 **APPLICANT** LIST OF REFERENCES CITED BY APPLICANT Christine MEUNIER **FILING DATE GROUP** March 31, 2004 1615 **U.S. PATENT DOCUMENTS EXAMINER** DOCUMENT SUB FILING DATE DATE NAME CLASS INITIAL NUMBER CLASS IF APPROPRIATE /B.S.F./ 2004/0219123 11/4/04 AA Astruc, et al. 5/30/02 AB 2002/0064540 Allec, et al. AC 2002/0054928 5/9/02 Picard-Lesboueyries 9/3/96 AD 5.552,446 Candau, et al. ΑE 6,007,799 12/28/99 Lee, et al. /B.S.F./ AF 6,294,157 9/25/01 Rubinstenn, et al. AG AH ΑI AJ ΑK AL MA AN **FOREIGN PATENT DOCUMENTS TRANSLATION** DOCUMENT DATE COUNTRY NUMBER NO 7B.S.F./ AO JP2003-81757 3/19/03 Japan (English Abstract Provided) X AP JP2003-81758 3/19/03 Japan (English Abstract Provided) X AQ 2/22/00 JP2000-53555 Japan (English Abstract Provided) X AR JP7-256086 10/9/95 Japan (Equivalent to US 5,552,446) X AS JP10-324616 12/8/98 Japan (Equivalent to EP0875235) X

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Date Considered 09/17/2007

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

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/Barbara S. Frazier/

Examiner

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